


<b>Search Notes</b>  	<b>Application/Control No.</b>  10561610	<b>Applicant(s)/Patent Under Reexamination</b>  NAGANO ET AL.
	<b>Examiner</b>  Hsieh, Ping Y	<b>Art Unit</b>  2618

SEARCHED			
Class	Subclass	Date	Examiner
455	62,63.3,78,82,83	5/1/08	PH

SEARCH NOTES		
Search Notes	Date	Examiner
Consulted with Yuwen Pan	12/06/07	PH
Text search in EAST (see search history)	5/1/08	PH
PLUS search	12/06/07	PH

INTERFERENCE SEARCH			
Class	Subclass	Date	Examiner